

Geometric Motion in Epitaxial Phenomena

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Outline

Introduction

Epitaxy techniques growth modes

Submonolayer Growth

Island morphologies

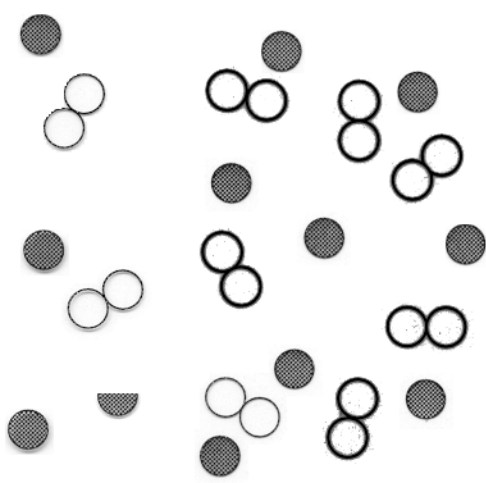
Island-size distributions

Multilayer Growth

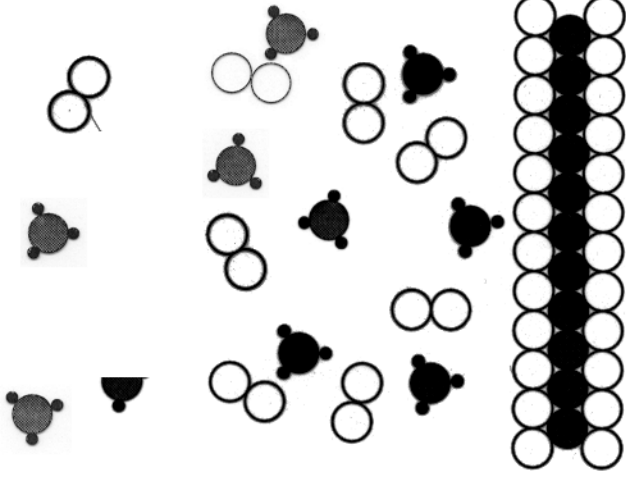
Kinetic roughening

Stranski Krastanov growth

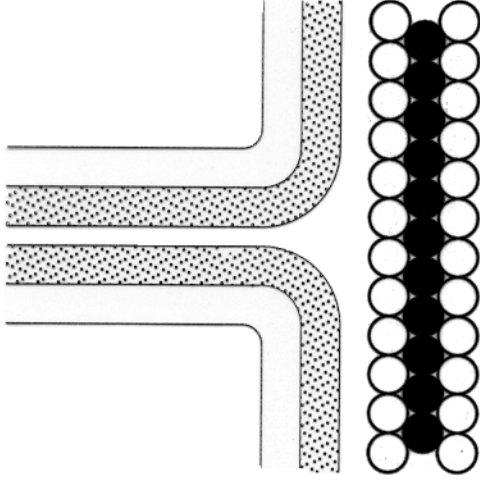
Summary



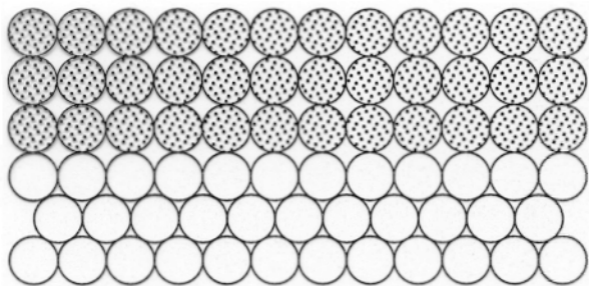
Molecular-Beam Epitaxy



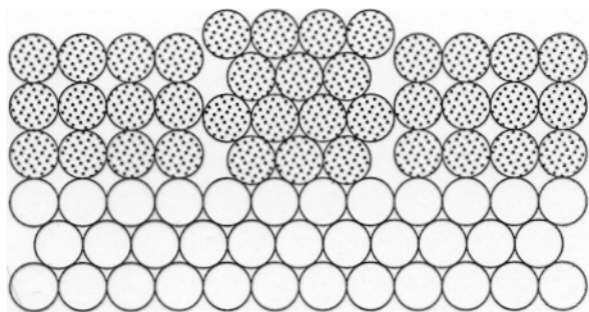
Chemical-Beam Epitaxy



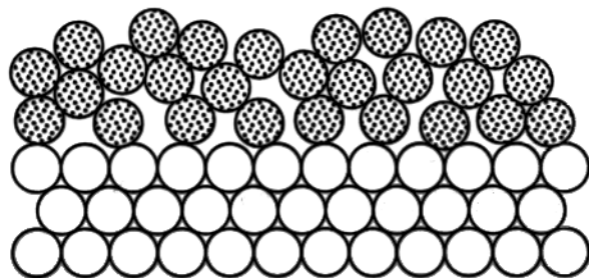
Metalorganic Vapor-Phase Epitaxy



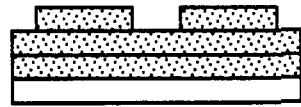
Epitaxial



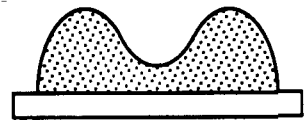
Polycrystalline



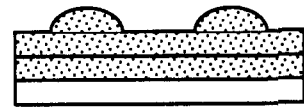
Amorphous



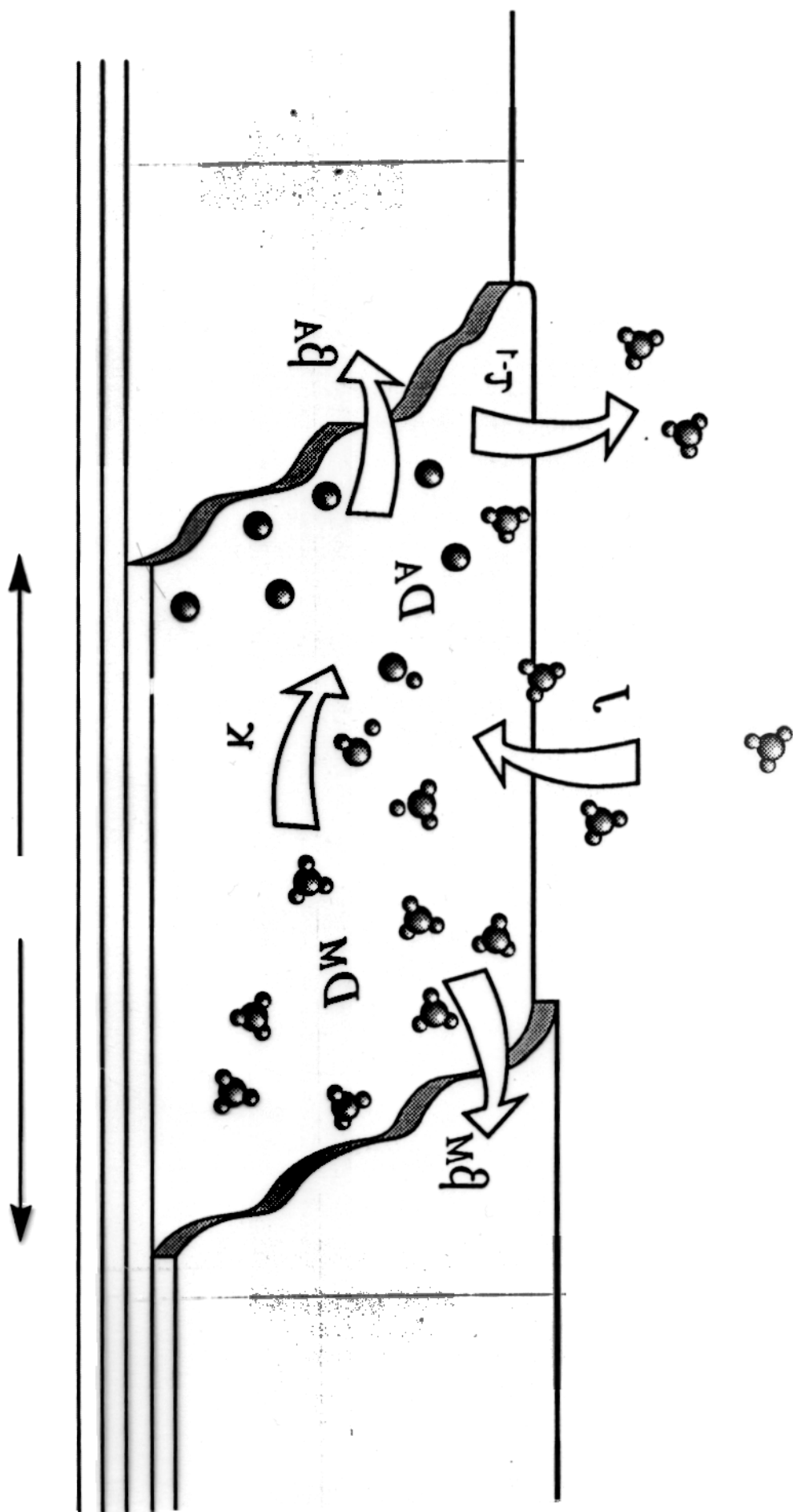
Frank-van der Merwe

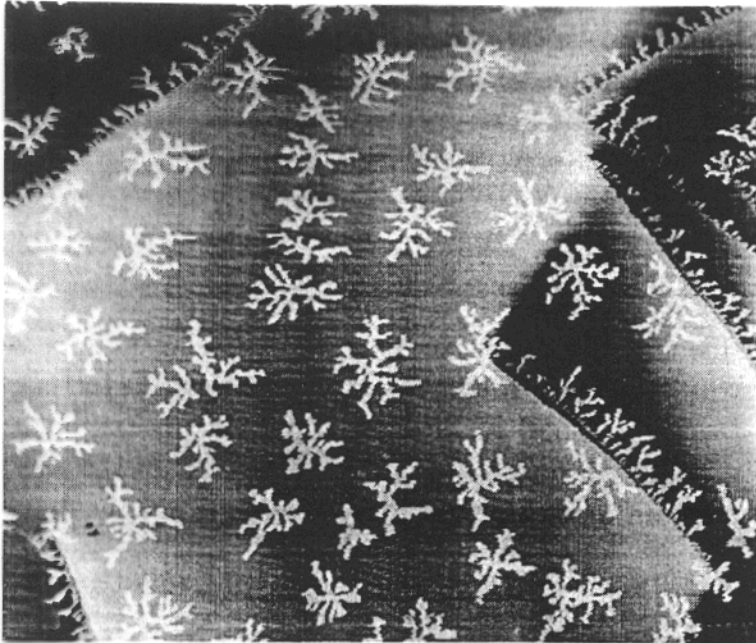


Volmer-Weber



Stranski-Krastanov

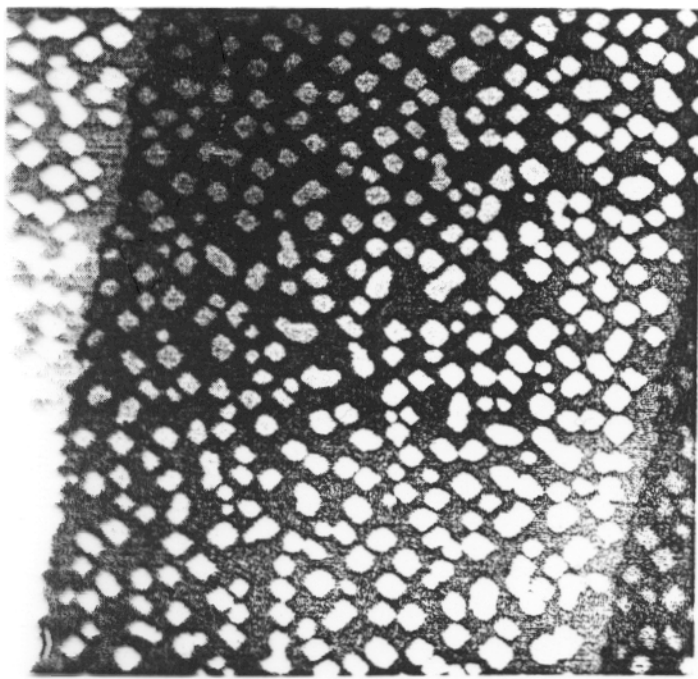




Au/Ru(0001)

$$\beta \approx 1.7$$

Phys. Rev. Lett. 67, 3279 ('91)



Ni/Ni(001)

$$\beta \approx 2$$

J. Vac. Sci. Technol. A 10,
1970 ('92)

Rate Equations

(Irreversible Aggregation)

$$\frac{dn_1}{dt} = F - 2D\sigma_1 n_1^2 - Dn_1 \sum_{s=2}^{\infty} \sigma_s n_s$$

$$\frac{dn_s}{dt} = Dn_1 \sigma_{s-1} n_{s-1} - Dn_1 \sigma_s n_s$$

n_1 adatom density

n_s density of islands with s atoms

F deposition flux

D surface diffusion constant

σ_s capture numbers



contain spatial information about local environment

Scaling Laws

For large $R = D/F$, with $\theta = Ft$,

$$n_1 \sim \theta^{-r} R^{-\omega} \quad (\text{adatom density})$$

$$s_{av} \sim \theta^z R^x \quad (\text{average island size})$$

$$N \sim \theta^{1-z} R^{-x} \quad (\text{total island density})$$

$$n_s(\theta) = \frac{\theta}{s_{av}^2} f(s/s_{av}) \quad (\text{individual island size})$$

Exponents and scaling function are universal,

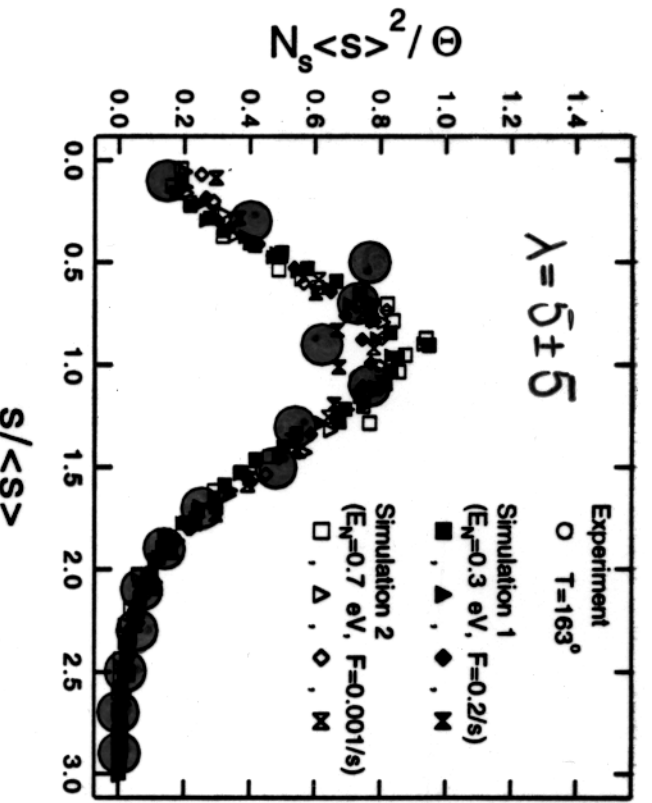
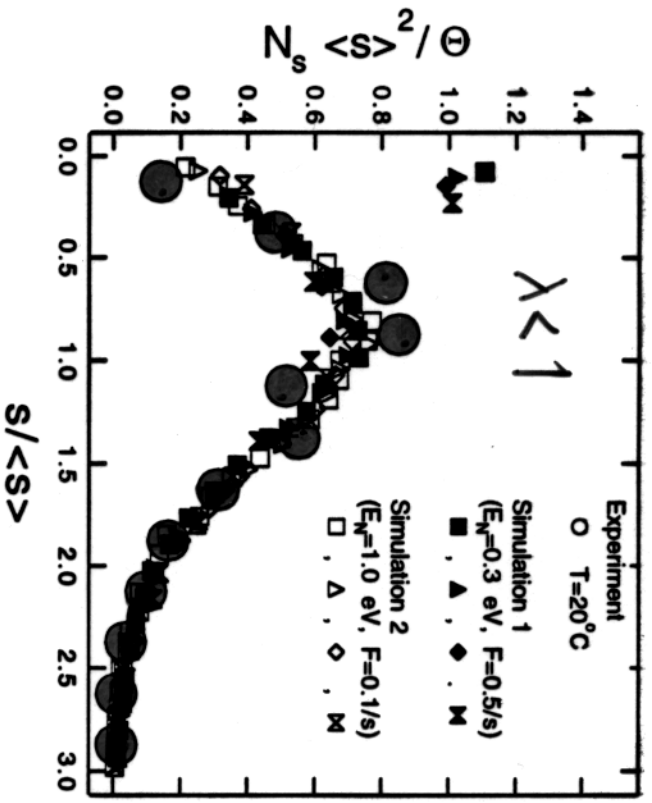
but depend on processes:

detachment

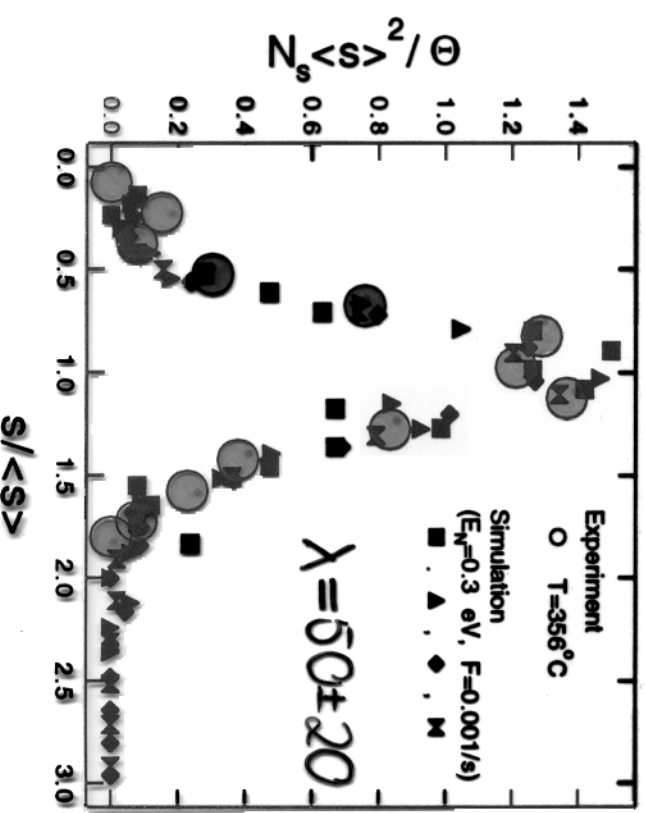
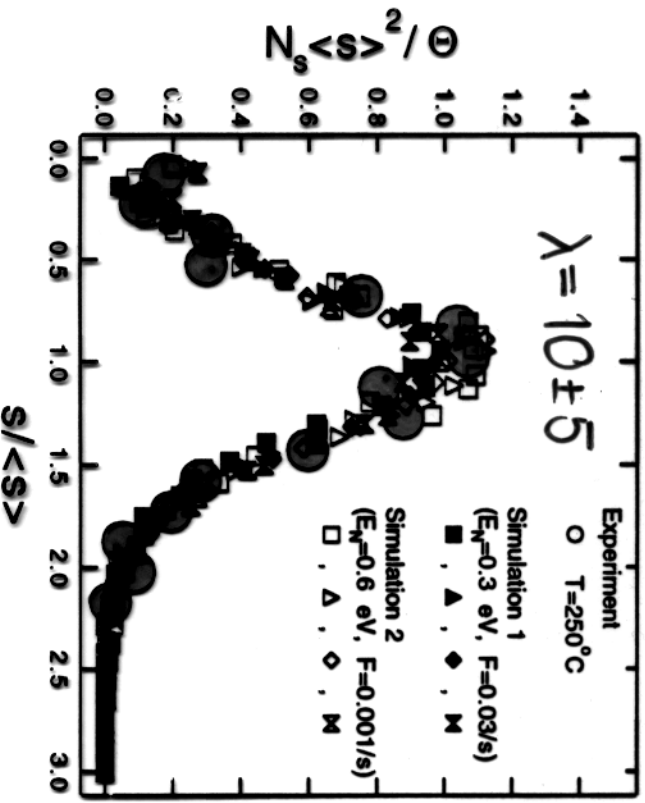
evaporation

inhomogeneous nucleation

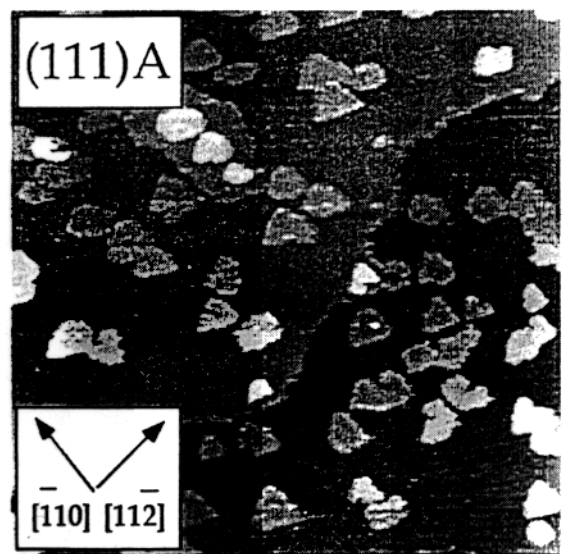
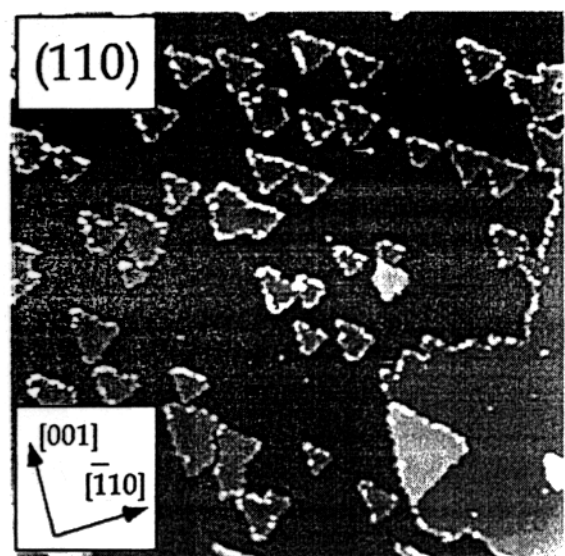
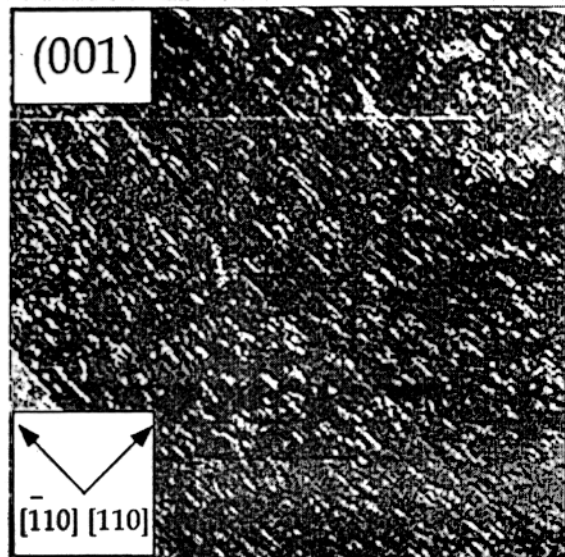
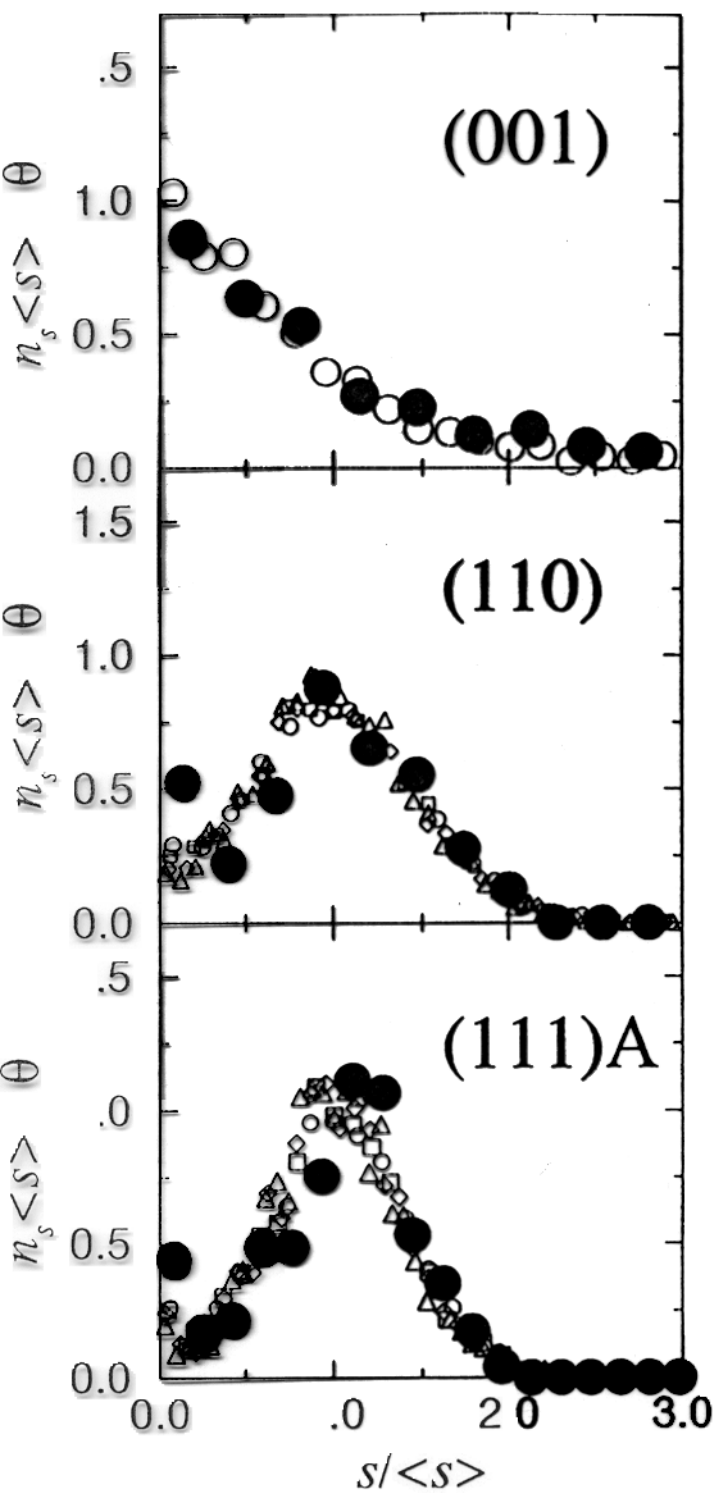
4. island mobility



$$\lambda = N_1 e^{E_N/kT}$$



Stroscio and Pierce, Phys. Rev. B. 49, 8522 (1994); STM on Fe/Fe(001)



Island Dynamics (and Level Sets)

$$\frac{\partial n_1}{\partial t} = F + D \nabla^2 n_1 \approx 2 \frac{dN}{dt}$$

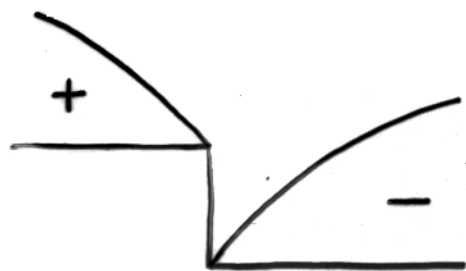
$n_1(x, t) = 0$ for $\vec{x} \in$ island boundary

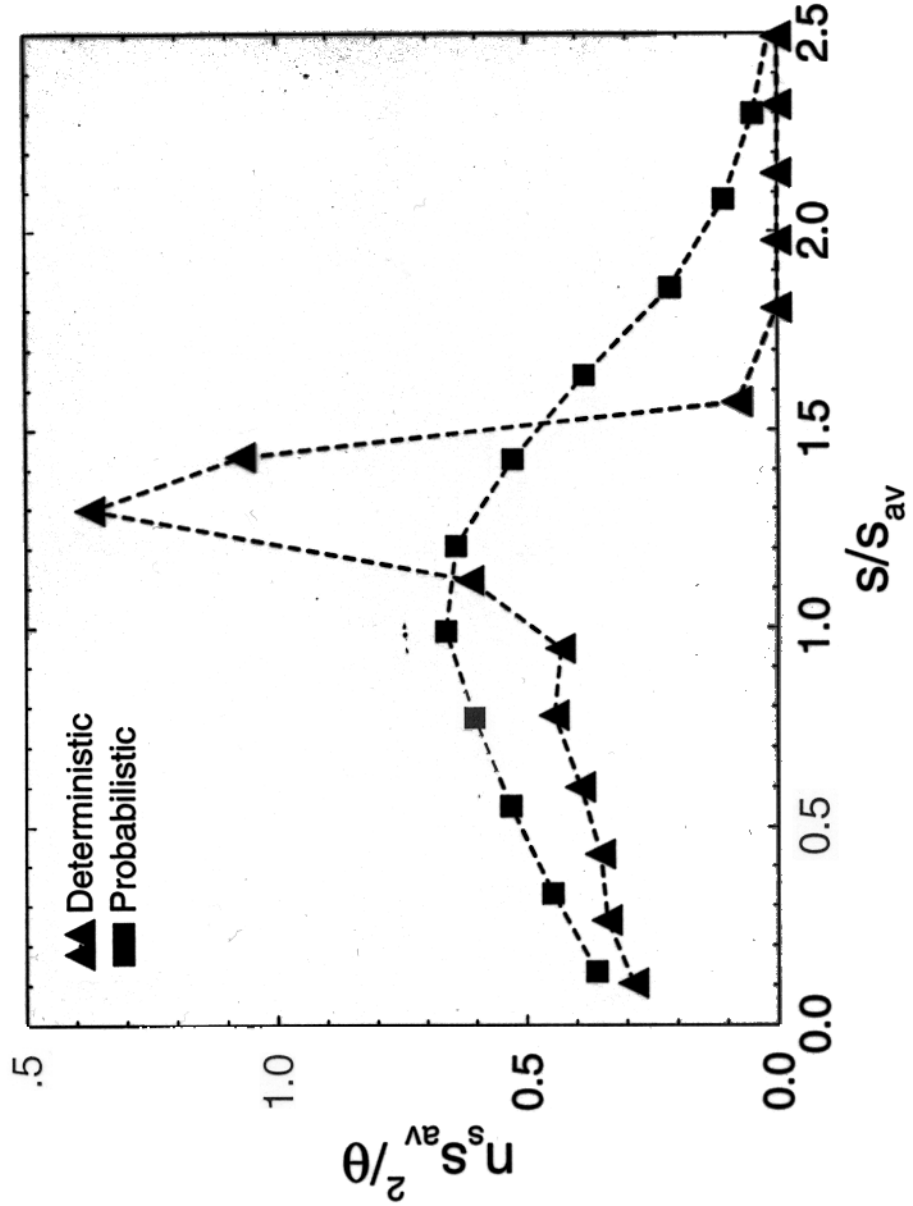
$$\frac{dN}{dt} = D \sigma \langle n_1^2 \rangle$$

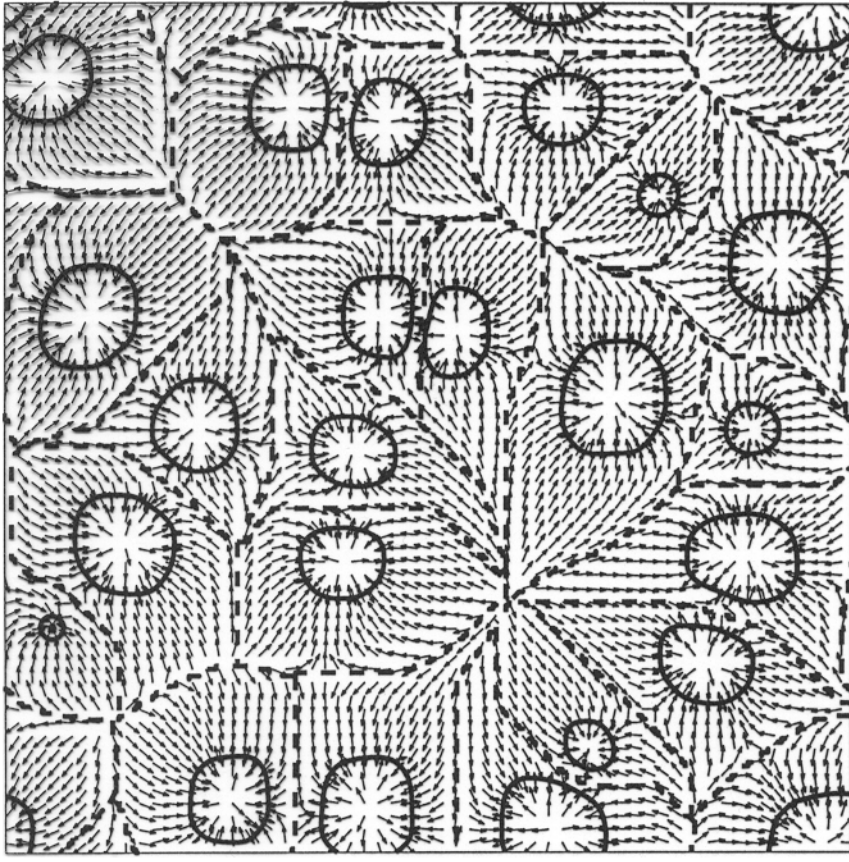
Method of Solution

$$\frac{\partial \varphi}{\partial t} + v \nabla \varphi = 0$$

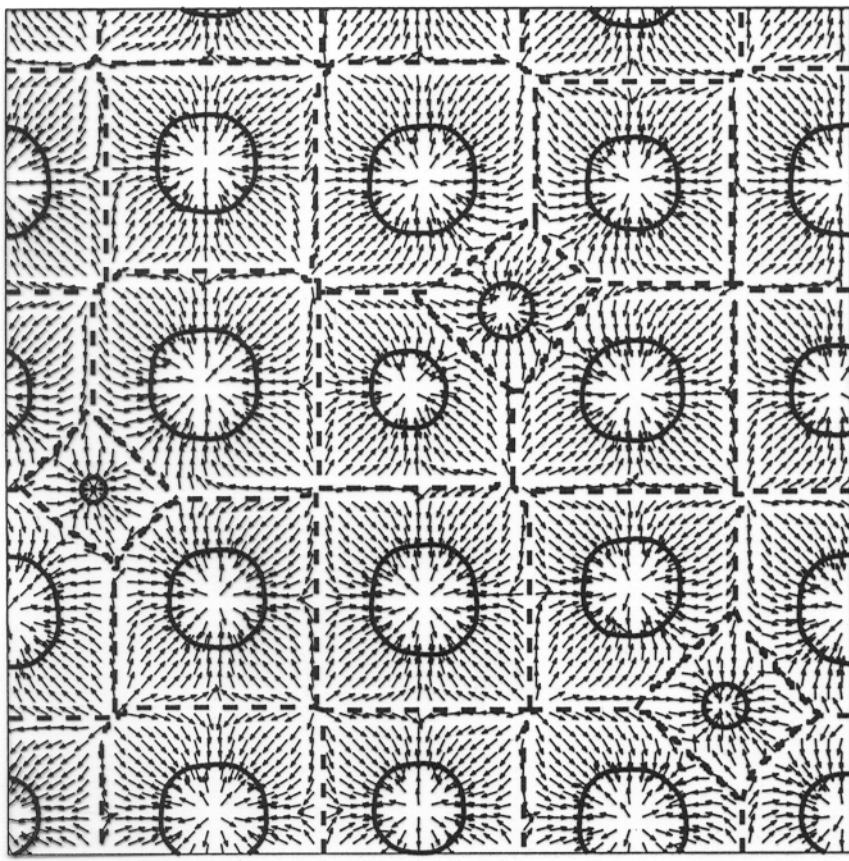
$$v_n = a^2 D (\hat{n} \cdot \vec{\nabla} n_1^- - \hat{n} \cdot \nabla n_1^+)$$





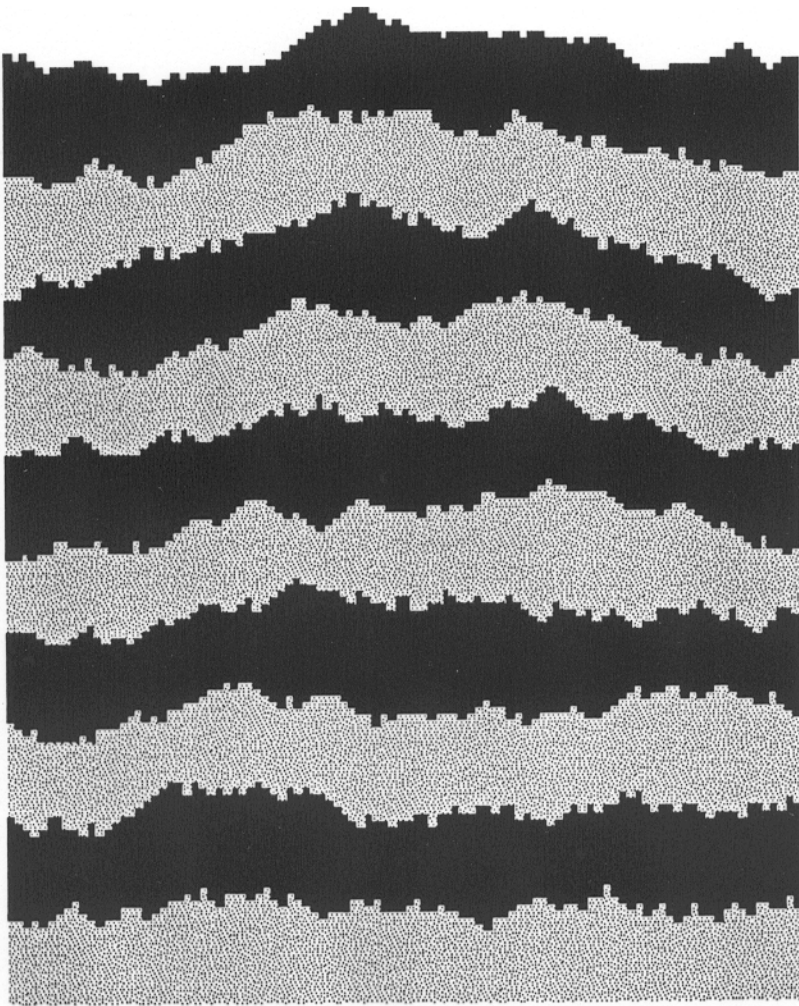


Stochastic Seeding



Deterministic Seeding

Kinetic Roughening



Random deposition + relaxation
to local height minimum (Edwards Wilkinson)

Barabási and Stanley Fractal Concepts in Surface Growth, p 45.

Kinetic Roughening

dynamic scaling hypothesis)

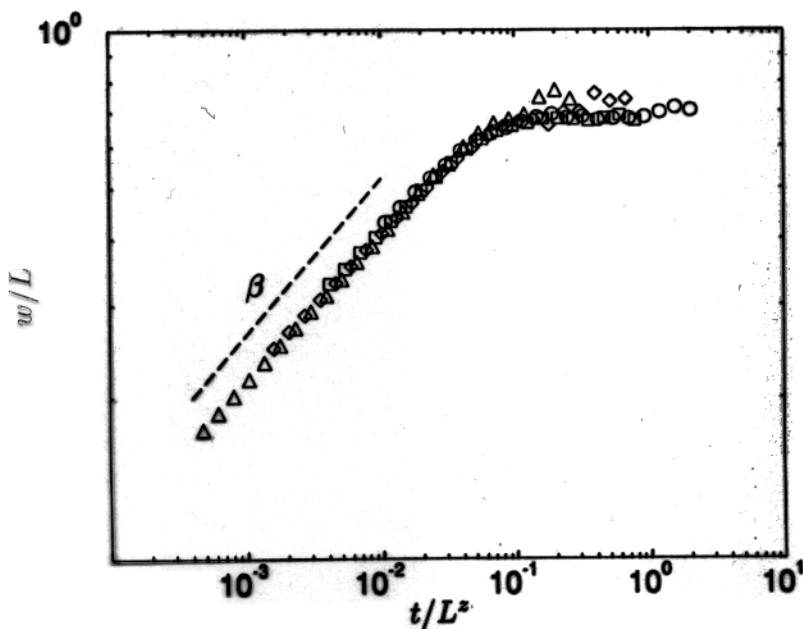
$$W(L, t) \left\{ \langle h^2 \rangle - \langle h \rangle^2 \right\}^{1/2} \sim L^\alpha f(t/L^z)$$

$h(\vec{x}, t)$ surface height at position x at time t

lateral viewing scale

$$\text{scaling function} \sim \begin{cases} x^\beta, & x \ll \\ \text{constant}, & x \gg \end{cases}$$

α roughness exponent } $z = \frac{\alpha}{\beta}$ dynamic exponent
 β growth exponent



Stochastic Equations of Motion

The problem to express discrete rule-based models as stochastic DEs

Such equations are expected to have the form

$$\frac{\partial h}{\partial t} = \gamma \nabla^2 h + \lambda (\nabla h)^2 + K \nabla^4 h + \sigma \nabla^2 (\nabla h)^2 + F + \eta$$

where

height of interface at position \vec{x} at time t

Gaussian noise

Physical processes

γ : desorption EW/relaxation

λ desorption

K, σ diffusion

F net flux

Passage across Length/Time Scales

Transition rules for atomistic lattice model (KMC)

||

Master equation for $P(H, t)$ $\equiv \{h_1, h_2, \dots\}$

Kurtz theorems



van Kampen Ω -expansion

Discrete Fokker-Planck/Langevin equation



?

Continuum Equation of Motion

Summary

Three levels of scaling

fractal islands island-size distributions,
kinetic roughening

Epitaxial phenomena

stochastic behavior + geometric motion

Multiscale modelling

atomistic processes \longrightarrow interface motion

Future work

development/application of analysis numerical
methods stochastic analysis/probability,...